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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	4620
Number of Logic Elements/Cells	73920
Total RAM Bits	4257792
Number of I/O	310
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx75df27c7n

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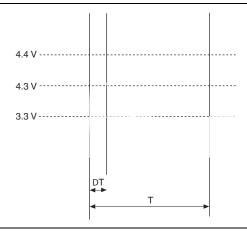
A DC signal is equivalent to 100% duty cycle. For example, a signal that overshoots to 4.3 V can only be at 4.3 V for 65% over the lifetime of the device; for a device lifetime of 10 years, this amounts to 65/10ths of a year.

Table 1–2. Maximum Allowed Overshoot During Transitions over a 10-Year Time Frame for Cyclone IV Devices

Symbol	Parameter	Condition (V)	Overshoot Duration as % of High Time	Unit
		V _I = 4.20	100	%
		V _I = 4.25	98	%
		V _I = 4.30	65	%
	40 1	V _I = 4.35	43	%
V _i	AC Input Voltage	V _I = 4.40	29	%
	Voltago	V _I = 4.45	20	%
		V _I = 4.50	13	%
		V _I = 4.55	9	%
		V _I = 4.60	6	%

Figure 1–1 shows the methodology to determine the overshoot duration. The overshoot voltage is shown in red and is present on the input pin of the Cyclone IV device at over 4.3 V but below 4.4 V. From Table 1–2, for an overshoot of 4.3 V, the percentage of high time for the overshoot can be as high as 65% over a 10-year period. Percentage of high time is calculated as ([delta T]/T) \times 100. This 10-year period assumes that the device is always turned on with 100% I/O toggle rate and 50% duty cycle signal. For lower I/O toggle rates and situations in which the device is in an idle state, lifetimes are increased.

Figure 1-1. Cyclone IV Devices Overshoot Duration



Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Cyclone IV devices. Table 1–3 and Table 1–4 list the steady-state voltage and current values expected from Cyclone IV E and Cyclone IV GX devices. All supplies must be strictly monotonic without plateaus.

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices (1), (2) (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CCINT} (3)	Supply voltage for internal logic, 1.2-V operation	_	1.15	1.2	1.25	V
VCCINT 19	Supply voltage for internal logic, 1.0-V operation	_	0.97	1.0	1.03	V
	Supply voltage for output buffers, 3.3-V operation	_	3.135	3.3	3.465	V
	Supply voltage for output buffers, 3.0-V operation	_	2.85	3	3.15	V
V _{CCIO} (3), (4)	Supply voltage for output buffers, 2.5-V operation	_	2.375	2.5	2.625	V
VCCIO (57)	Supply voltage for output buffers, 1.8-V operation	_	1.71	1.8	1.89	V
	Supply voltage for output buffers, 1.5-V operation	_	1.425	1.5	1.575	V
	Supply voltage for output buffers, 1.2-V operation	_	1.14	1.2	1.26	V
V _{CCA} (3)	Supply (analog) voltage for PLL regulator	_	2.375	2.5	2.625	V
V (3)	Supply (digital) voltage for PLL, 1.2-V operation	_	1.15	1.2	1.25	V
V _{CCD_PLL} (3)	Supply (digital) voltage for PLL, 1.0-V operation	_	0.97	1.0	1.03	V
V _I	Input voltage	_	-0.5	_	3.6	V
V ₀	Output voltage	_	0	_	V _{CCIO}	V
		For commercial use	0	_	85	°C
т	Operating junction towns and the	For industrial use	-40	_	100	°C
T_J	Operating junction temperature	For extended temperature	-40	_	125	°C
		For automotive use	-40	_	125	°C
t _{RAMP}	Power supply ramp time	Standard power-on reset (POR) (5)	50 μs	_	50 ms	_
		Fast POR (6)	50 μs	_	3 ms	_

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices (1), (2) (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I _{Diode}	Magnitude of DC current across PCI-clamp diode when enable	_	_	_	10	mA

Notes to Table 1-3:

- (1) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades.
- (2) V_{CCIO} for all I/O banks must be powered up during device operation. All VCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.
- (3) V_{CC} must rise monotonically.
- (4) V_{CCIO} powers all input buffers.
- (5) The POR time for Standard POR ranges between 50 and 200 ms. Each individual power supply must reach the recommended operating range within 50 ms.
- (6) The POR time for Fast POR ranges between 3 and 9 ms. Each individual power supply must reach the recommended operating range within 3 ms.

Table 1-4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CCINT} (3)	Core voltage, PCIe hard IP block, and transceiver PCS power supply	_	1.16	1.2	1.24	V
V _{CCA} (1), (3)	PLL analog power supply	_	2.375	2.5	2.625	V
V _{CCD_PLL} (2)	PLL digital power supply	_	1.16	1.2	1.24	V
	I/O banks power supply for 3.3-V operation	_	3.135	3.3	3.465	V
	I/O banks power supply for 3.0-V operation	_	2.85	3	3.15	V
V _{CCIO} (3), (4)	I/O banks power supply for 2.5-V operation	_	2.375	2.5	2.625	V
vccio (2)	I/O banks power supply for 1.8-V operation	_	1.71	1.8	1.89	V
	I/O banks power supply for 1.5-V operation	_	1.425	1.5	1.575	V
	I/O banks power supply for 1.2-V operation	_	1.14	1.2	1.26	V
	Differential clock input pins power supply for 3.3-V operation	_	3.135	3.3	3.465	V
	Differential clock input pins power supply for 3.0-V operation	_	2.85	3	3.15	V
V _{CC_CLKIN}	Differential clock input pins power supply for 2.5-V operation	_	2.375	2.5	2.625	V
(3), (5), (6)	Differential clock input pins power supply for 1.8-V operation	_	1.71	1.8	1.89	V
	Differential clock input pins power supply for 1.5-V operation	_	1.425	1.5	1.575	V
	Differential clock input pins power supply for 1.2-V operation	_	1.14	1.2	1.26	V
V_{CCH_GXB}	Transceiver output buffer power supply	_	2.375	2.5	2.625	V

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2) (1)

			V _{CCIO} (V)											
Parameter	Condition	1	.2	1	.5	1	.8	2	.5	3	.0	3	.3	Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	_	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1-7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

Table 1-8. Series OCT Without Calibration Specifications for Cyclone IV Devices

			Resistance Tolerance			
Description	V _{CCIO} (V)	Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	Unit		
	3.0	±30	±40	%		
0 · 00 T ···	2.5	±30	±40	%		
Series OCT without calibration	1.8	±40	±50	%		
Calibration	1.5	±50	±50	%		
	1.2	±50	±50	%		

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

Table 1–9. Series OCT with Calibration at Device Power-Up Specifications for Cyclone IV Devices

	Commercial Maximum industrial, a		Calibration Accuracy			
Description			Industrial, Extended industrial, and Automotive Maximum	Unit		
	3.0	±10	±10	%		
Series OCT with	2.5	±10	±10	%		
calibration at device	1.8	±10	±10	%		
power-up	1.5	±10	±10	%		
	1.2	±10	±10	%		

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up. Use Table 1–10 and Equation 1–1 to determine the final OCT resistance considering the variations after calibration at device power-up. Table 1–10 lists the change percentage of the OCT resistance with voltage and temperature.

Table 1–10. OCT Variation After Calibration at Device Power-Up for Cyclone IV Devices

Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	-0.026
2.5	0.234	-0.039
1.8	0.219	-0.086
1.5	0.199	-0.136
1.2	0.161	-0.288

Equation 1-1. Final OCT Resistance (1), (2), (3), (4), (5), (6)

Notes to Equation 1-1:

- (1) T_2 is the final temperature.
- (2) T_1 is the initial temperature.
- (3) MF is multiplication factor.
- (4) R_{final} is final resistance.
- (5) R_{initial} is initial resistance.
- (6) Subscript $_{\rm X}$ refers to both $_{\rm V}$ and $_{\rm T}$.
- (7) ΔR_V is a variation of resistance with voltage.
- (8) ΔR_T is a variation of resistance with temperature.
- (9) dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
- (10) dR/dV is the change percentage of resistance with voltage after calibration at device power-up.
- (11) V2 is final voltage.
- (12) V_1 is the initial voltage.

Operating Conditions

Example 1–1 shows how to calculate the change of 50- Ω I/O impedance from 25°C at 3.0 V to 85°C at 3.15 V.

Example 1-1. Impedance Change

$$\Delta R_V = (3.15 - 3) \times 1000 \times -0.026 = -3.83$$

$$\Delta R_T = (85 - 25) \times 0.262 = 15.72$$

Because ΔR_V is negative,

$$MF_V = 1 / (3.83/100 + 1) = 0.963$$

Because ΔR_T is positive,

$$MF_T = 15.72/100 + 1 = 1.157$$

$$MF = 0.963 \times 1.157 = 1.114$$

$$R_{final} = 50 \times 1.114 = 55.71 \Omega$$

Pin Capacitance

Table 1–11 lists the pin capacitance for Cyclone IV devices.

Table 1–11. Pin Capacitance for Cyclone IV Devices (1)

Symbol	Parameter	Typical – Quad Flat Pack (QFP)	Typical – Quad Flat No Leads (QFN)	Typical – Ball-Grid Array (BGA)	Unit
C _{IOTB}	Input capacitance on top and bottom I/O pins	7	7	6	pF
C _{IOLR}	Input capacitance on right I/O pins	7	7	5	pF
C _{LVDSLR}	Input capacitance on right I/O pins with dedicated LVDS output	8	8	7	pF
C _{VREFLR} (2)	Input capacitance on right dual-purpose $\ensuremath{\mathtt{VREF}}$ pin when used as V_{REF} or user I/O pin	21	21	21	pF
C _{VREFTB} (2)	Input capacitance on top and bottom dual-purpose ${\tt VREF}$ pin when used as $V_{{\tt REF}}$ or user I/O pin	23 (3)	23	23	pF
C _{CLKTB}	Input capacitance on top and bottom dedicated clock input pins	7	7	6	pF
C _{CLKLR}	Input capacitance on right dedicated clock input pins	6	6	5	pF

Notes to Table 1-11:

- (1) The pin capacitance applies to FBGA, UBGA, and MBGA packages.
- (2) When you use the VREF pin as a regular input or output, you can expect a reduced performance of toggle rate and t_{CO} because of higher pin capacitance.
- (3) C_{VREFTB} for the EP4CE22 device is 30 pF.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1-12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1–12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices (1)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (2), (3)	7	25	41	kΩ
	Value of the I/O pin pull-up resistor	$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (2), (3)	7	28	47	kΩ
D	before and during configuration, as	$V_{CCIO} = 2.5 \text{ V} \pm 5\%$ (2), (3)	8	35	61	kΩ
R_ _{PU}	well as user mode if you enable the programmable pull-up resistor option	$V_{CCIO} = 1.8 \text{ V} \pm 5\%$ (2), (3)	10	57	108	kΩ
		$V_{CCIO} = 1.5 \text{ V} \pm 5\%$ (2), (3)	13	82	163	kΩ
		$V_{CCIO} = 1.2 \text{ V} \pm 5\%$ (2), (3)	19	143	351	kΩ
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (4)	6	19	30	kΩ
	Value of the 1/O air well decreased as	$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (4)	6	22	36	kΩ
R_PD	Value of the I/O pin pull-down resistor before and during configuration	$V_{CCIO} = 2.5 \text{ V} \pm 5\%$ (4)	6	25	43	kΩ
	bololo and daring configuration	$V_{CCIO} = 1.8 \text{ V} \pm 5\%$ (4)	7	35	71	kΩ
		$V_{CCIO} = 1.5 \text{ V} \pm 5\%$ (4)	8	50	112	kΩ

Notes to Table 1-12:

- (1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (3) $R_{PU} = (V_{CC10} V_1)/I_{R_PU}$ Minimum condition: $-40^{\circ}C$; $V_{CC10} = V_{CC} + 5\%$, $V_1 = V_{CC} + 5\% 50$ mV; Typical condition: $25^{\circ}C$; $V_{CC10} = V_{CC}$, $V_1 = 0$ V; $V_2 = 0$ V; $V_3 = 0$ V; $V_4 = 0$ V and $V_5 = 0$ V and $V_6 = 0$ V and $V_7 = 0$ V and $V_8 = 0$ V and $V_$

Maximum condition: 100°C ; $V_{\text{CCIO}} = V_{\text{CC}} - 5\%$, $V_{\text{I}} = 0$ V; in which V_{I} refers to the input voltage at the I/O pin.

(4) $R_{PD} = V_I/I_{RPD}$

Minimum condition: -40°C; $V_{CCIO} = V_{CC} + 5\%$, $V_I = 50$ mV;

Typical condition: 25°C; $V_{CCIO} = V_{CC}$, $V_1 = V_{CC} - 5\%$; Maximum condition: 100°C; $V_{CCIO} = V_{CC} - 5\%$, $V_1 = V_{CC} - 5\%$; in which V_1 refers to the input voltage at the I/O pin.

Hot-Socketing

Table 1–13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1–13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
I _{IOPIN(DC)}	DC current per I/O pin	300 μΑ
I _{IOPIN(AC)}	AC current per I/O pin	8 mA (1)
I _{XCVRTX(DC)}	DC current per transceiver TX pin	100 mA
I _{XCVRRX(DC)}	DC current per transceiver RX pin	50 mA

Note to Table 1-13:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|IIOPIN| = C \frac{dv}{dt}$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

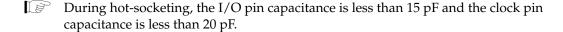


Table 1–16. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Cyclone IV Devices (1)

1/0)		V _{REF} (V)		V _{TT} (V) ⁽²⁾				
Standard	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max		
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} – 0.04	V_{REF}	V _{REF} + 0.04		
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04		
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95		
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79		
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 x V _{CCIO} (3) 0.47 x V _{CCIO} (4)	0.5 x V _{CCIO} (3) 0.5 x V _{CCIO} (4)	0.52 x V _{CCIO} (3) 0.53 x V _{CCIO} (4)	_	0.5 x V _{CCIO}	_		

Notes to Table 1-16:

- (1) For an explanation of terms used in Table 1–16, refer to "Glossary" on page 1–37.
- (2) V_{TT} of the transmitting device must track V_{REF} of the receiving device.
- (3) Value shown refers to DC input reference voltage, $V_{REF(DC)}$.
- (4) Value shown refers to AC input reference voltage, $V_{REF(AC)}$.

Table 1-17. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Cyclone IV Devices

I/O	V _{IL(}	_{DC)} (V)	VIH	_{I(DC)} (V)	V _{IL(}	_(AC) (V)	V _{IH}	(AC) (V)	V _{OL} (V)	V _{OH} (V)	I _{OL}	I _{OH}
Standard	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min	(mĀ)	(mÄ)
SSTL-2 Class I	_	V _{REF} – 0.18	V _{REF} + 0.18	_	_	V _{REF} – 0.35	V _{REF} + 0.35	_	V _{ττ} – 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	_	V _{REF} – 0.18	V _{REF} + 0.18	_	_	V _{REF} – 0.35	V _{REF} + 0.35	_	V _{TT} – 0.76	V _{TT} + 0.76	16.4	-16.4
SSTL-18 Class I		V _{REF} – 0.125	V _{REF} + 0.125	_		V _{REF} – 0.25	V _{REF} + 0.25	_	V _{TT} – 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	_	V _{REF} – 0.125	V _{REF} + 0.125	_	_	V _{REF} – 0.25	V _{REF} + 0.25	_	0.28	V _{CCIO} - 0.28	13.4	-13.4
HSTL-18 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCIO} - 0.4	8	-8
HSTL-18 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCIO} - 0.4	16	-16
HSTL-15 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCIO} - 0.4	8	-8
HSTL-15 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 3 of 4)

Symbol/	0 1111		C6			C7, I7			11		
Description	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Signal detect/loss threshold	PIPE mode	65	_	175	65	_	175	65	_	175	mV
t _{LTR} (10)	_	_	_	75	_	_	75	_	_	75	μs
t _{LTR-LTD_Manual} (11)	_	15	_	_	15	_	_	15	_	_	μs
t _{LTD} (12)	_	0	100	4000	0	100	4000	0	100	4000	ns
t _{LTD_Manual} (13)	_		_	4000	_		4000	_		4000	ns
t _{LTD_Auto} (14)	_		_	4000	_		4000	_		4000	ns
Receiver buffer and CDR offset cancellation time (per channel)	_		_	17000	_	_	17000	_	_	17000	recon fig_c lk cycles
	DC Gain Setting = 0	_	0	_	_	0	_	_	0	_	dB
Programmable DC gain	DC Gain Setting = 1	_	3	_	_	3	_	_	3	_	dB
	DC Gain Setting = 2	_	6	_	_	6	_	_	6	_	dB
Transmitter											
Supported I/O Standards	1.5 V PCML										
Data rate (F324 and smaller package)	_	600	_	2500	600	_	2500	600	_	2500	Mbps
Data rate (F484 and larger package)	_	600	_	3125	600	_	3125	600	_	2500	Mbps
V _{OCM}	0.65 V setting	_	650	_	_	650	_	_	650	_	mV
Differential on-chip	100–Ω setting	_	100	_	_	100	_	_	100	_	Ω
termination resistors	150– Ω setting	_	150	_	_	150	_	_	150	_	Ω
Differential and common mode return loss	PIPE, CPRI LV, Serial Rapid I/O SR, SDI, XAUI, SATA					Complian	į			,	_
Rise time	_	50	_	200	50	_	200	50	_	200	ps
Fall time	_	50	_	200	50	_	200	50	_	200	ps
Intra-differential pair skew	_	_	_	15	_	_	15	_	_	15	ps
Intra-transceiver block skew	_	_	_	120	_	_	120	_	_	120	ps

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 4 of 4)

Symbol/	Conditions -		C6			C7, I7			Unit		
Description	Collultions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
PLD-Transceiver Inte	rface										
Interface speed (F324 and smaller package)	_	25	_	125	25	_	125	25	_	125	MHz
Interface speed (F484 and larger package)	_	25	_	156.25	25	_	156.25	25	_	156.25	MHz
Digital reset pulse width	_				Minimu	m is 2 pa	rallel clock	cycles			

Notes to Table 1-21:

- (1) This specification is valid for transmitter output jitter specification with a maximum total jitter value of 112 ps, typically for 3.125 Gbps SRIO and XAUI protocols.
- (2) The minimum reconfig_clk frequency is 2.5 MHz if the transceiver channel is configured in **Transmitter Only** mode. The minimum reconfig_clk frequency is 37.5 MHz if the transceiver channel is configured in **Receiver Only** or **Receiver and Transmitter** mode.
- (3) The device cannot tolerate prolonged operation at this absolute maximum.
- (4) The rate matcher supports only up to ±300 parts per million (ppm).
- (5) Supported for the F169 and F324 device packages only.
- (6) Supported for the F484, F672, and F896 device packages only. Pending device characterization.
- (7) To support CDR ppm tolerance greater than ±300 ppm, implement ppm detector in user logic and configure CDR to Manual Lock Mode.
- (8) Asynchronous spread-spectrum clocking is not supported.
- (9) For the EP4CGX30 (F484 package only), EP4CGX50, and EP4CGX75 devices, the CDR ppl tolerance is ±200 ppm.
- (10) Time taken until pll locked goes high after pll powerdown deasserts.
- (11) Time that the CDR must be kept in lock-to-reference mode after rx analogreset deasserts and before rx locktodata is asserted in manual mode.
- (12) Time taken to recover valid data after the rx_locktodata signal is asserted in manual mode (Figure 1–2), or after rx_freqlocked signal goes high in automatic mode (Figure 1–3).
- (13) Time taken to recover valid data after the $rx_locktodata$ signal is asserted in manual mode.
- (14) Time taken to recover valid data after the $rx_freqlocked$ signal goes high in automatic mode.
- (15) To support data rates lower than the minimum specification through oversampling, use the CDR in LTR mode only.

Davisa		Performance											
Device	C6	C 7	C8	C8L (1)	C9L (1)	17	I8L (1)	A7	Unit				
EP4CE55	500	437.5	402	362	265	437.5	362	_	MHz				
EP4CE75	500	437.5	402	362	265	437.5	362	_	MHz				
EP4CE115	_	437.5	402	362	265	437.5	362	_	MHz				
EP4CGX15	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX22	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX30	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX50	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX75	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX110	500	437.5	402	_	_	437.5	_	_	MHz				
EP4CGX150	500	437.5	402	_	_	437.5	_	_	MHz				

Note to Table 1-24:

PLL Specifications

Table 1–25 lists the PLL specifications for Cyclone IV devices when operating in the commercial junction temperature range (0°C to 85°C), the industrial junction temperature range (-40°C to 100°C), the extended industrial junction temperature range (-40°C to 125°C), and the automotive junction temperature range (-40°C to 125°C). For more information about the PLL block, refer to "Glossary" on page 1–37.

Table 1–25. PLL Specifications for Cyclone IV Devices (1), (2) (Part 1 of 2)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (-6, -7, -8 speed grades)	5	_	472.5	MHz
f _{IN} (3)	Input clock frequency (-8L speed grade)	5	_	362	MHz
	Input clock frequency (-9L speed grade)	5	_	265	MHz
f _{INPFD}	PFD input frequency	5	_	325	MHz
f _{VCO} (4)	PLL internal VCO operating range	600	_	1300	MHz
f _{INDUTY}	Input clock duty cycle	40	_	60	%
t _{INJITTER_CCJ} (5)	Input clock cycle-to-cycle jitter F _{REF} ≥ 100 MHz	_	_	0.15	UI
	F _{REF} < 100 MHz	_	_	±750	ps
f _{OUT_EXT} (external clock output) (3)	PLL output frequency	_	_	472.5	MHz
	PLL output frequency (-6 speed grade)	_	_	472.5	MHz
	PLL output frequency (-7 speed grade)	_	_	450	MHz
f _{OUT} (to global clock)	PLL output frequency (-8 speed grade)	_	_	402.5	MHz
	PLL output frequency (-8L speed grade)	_	_	362	MHz
	PLL output frequency (-9L speed grade)	_	_	265	MHz
toutduty	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t _{LOCK}	Time required to lock from end of device configuration	_	_	1	ms

⁽¹⁾ Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades.

Table 1–25. PLL Specifications for Cyclone IV Devices (1), (2) (Part 2 of 2)

Symbol	Parameter	Min	Тур	Max	Unit
t _{DLOCK}	Time required to lock dynamically (after switchover, reconfiguring any non-post-scale counters/delays or areset is deasserted)	_	_	1	ms
toutjitter_period_dedclk (6)	Dedicated clock output period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	_	30	mUI
toutjitter_ccj_dedclk (6)	Dedicated clock output cycle-to-cycle jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	_	30	mUI
toutjitter_period_io (6)	Regular I/O period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	650	ps
	F _{OUT} < 100 MHz	_	_	75	mUI
toutjitter_ccj_io <i>(6)</i>	Regular I/O cycle-to-cycle jitter F _{OUT} ≥ 100 MHz	_	_	650	ps
	F _{OUT} < 100 MHz	_	_	75	mUI
t _{PLL_PSERR}	Accuracy of PLL phase shift	_	_	±50	ps
t _{ARESET}	Minimum pulse width on areset signal.	10	_	_	ns
tconfigpll	Time required to reconfigure scan chains for PLLs	_	3.5 (7)		SCANCLK cycles
f _{SCANCLK}	scanclk frequency	_	_	100	MHz
t _{CASC_OUTJITTER_PERIOD_DEDCLK}	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \ge 100 \text{ MHz}$)	_		425	ps
(8), (9)	Period jitter for dedicated clock output in cascaded PLLs (F _{OUT} < 100 MHz)	_	_	42.5	mUI

Notes to Table 1-25:

- (1) This table is applicable for general purpose PLLs and multipurpose PLLs.
- (2) You must connect $V_{CCD\ PLL}$ to V_{CCINT} through the decoupling capacitor and ferrite bead.
- (3) This parameter is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.
- (4) The V_{CO} frequency reported by the Quartus II software in the PLL Summary section of the compilation report takes into consideration the V_{CO} post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.
- (5) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source that is less than 200 ps.
- (6) Peak-to-peak jitter with a probability level of 10⁻¹² (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL when an input jitter of 30 ps is applied.
- (7) With 100-MHz scanclk frequency.
- $\begin{tabular}{ll} (8) & The cascaded PLLs specification is applicable only with the following conditions: \end{tabular}$
 - Upstream PLL—0.59 MHz \leq Upstream PLL bandwidth < 1 MHz
 - Downstream PLL—Downstream PLL bandwidth > 2 MHz
- (9) PLL cascading is not supported for transceiver applications.

Table 1–31. RSDS Transmitter Timing Specifications for Cyclone IV Devices (1), (2), (4) (Part 2 of 2)

Symbol M	Modes	C6			C7, I7			C8, A7			C8L, I8L					llnit	
	wodes	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
t _{LOCK} (3)	_	_		1	_	_	1	_		1	_	_	1	_		1	ms

Notes to Table 1-31:

- (1) Applicable for true RSDS and emulated RSDS_E_3R transmitter.
- (2) Cyclone IV E devices—true RSDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated RSDS transmitter is supported at the output pin of all I/O Banks.

 Cyclone IV GX devices—true RSDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated RSDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.
- (3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–32. Emulated RSDS_E_1R Transmitter Timing Specifications for Cyclone IV Devices (1), (3) (Part 1 of 2)

Ob.al	Madaa		C6			C7, 17	'		C8, A7	7	(C8L, 18	BL		C9L		11!4
Symbol	Modes	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
	×10	5	_	85	5		85	5		85	5		85	5	_	72.5	MHz
	×8	5	_	85	5	_	85	5	_	85	5		85	5	_	72.5	MHz
f _{HSCLK} (input clock	×7	5	_	85	5	_	85	5	_	85	5	_	85	5	_	72.5	MHz
frequency)	×4	5	_	85	5	_	85	5		85	5		85	5	_	72.5	MHz
	×2	5		85	5	_	85	5	_	85	5		85	5	_	72.5	MHz
	×1	5	_	170	5	_	170	5	_	170	5		170	5	_	145	MHz
	×10	100	_	170	100	_	170	100	_	170	100	_	170	100		145	Mbps
	×8	80	_	170	80	_	170	80	_	170	80	_	170	80	_	145	Mbps
Device operation in	×7	70	_	170	70	_	170	70	_	170	70		170	70	_	145	Mbps
Mbps	×4	40	_	170	40		170	40	_	170	40	_	170	40	_	145	Mbps
	×2	20	1	170	20	_	170	20		170	20		170	20		145	Mbps
	×1	10	-	170	10		170	10		170	10		170	10	_	145	Mbps
t _{DUTY}	_	45	_	55	45		55	45	_	55	45	_	55	45	_	55	%
TCCS	_	_	1	200	_	_	200	_		200	_		200	_		200	ps
Output jitter (peak to peak)	_	_		500	_	_	500	_		550	_	_	600	_		700	ps
	20 – 80%,																
t _{RISE}	C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500	—	ps
	20 – 80%,																
t _{FALL}	C _{LOAD} = 5 pF		500		_	500	_	_	500	_	_	500	_		500	_	ps

Symbol	Modes -	C6		C7, I7		C8,	A7	C8L,	, I8L	C	9L	Unit
Symbol	Modes	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	UIII
t _{DUTY}	_	45	55	45	55	45	55	45	55	45	55	%
TCCS	_	_	200	_	200	_	200	_	200	_	200	ps
Output jitter (peak to peak)	_	_	500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	_	_	1	_	1	_	1	_	1	_	1	ms

Notes to Table 1-35:

- (1) Cyclone IV E—emulated LVDS transmitter is supported at the output pin of all I/O Banks. Cyclone IV GX—emulated LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.
- (2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–36. LVDS Receiver Timing Specifications for Cyclone IV Devices (1), (3)

0	Modes	C6		C7, I7		C8, A7		C8L, I8L		C9L		1114
Symbol		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
	×10	10	437.5	10	370	10	320	10	320	10	250	MHz
	×8	10	437.5	10	370	10	320	10	320	10	250	MHz
f _{HSCLK} (input clock	×7	10	437.5	10	370	10	320	10	320	10	250	MHz
frequency)	×4	10	437.5	10	370	10	320	10	320	10	250	MHz
1 3,	×2	10	437.5	10	370	10	320	10	320	10	250	MHz
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	MHz
	×10	100	875	100	740	100	640	100	640	100	500	Mbps
	×8	80	875	80	740	80	640	80	640	80	500	Mbps
HSIODR	×7	70	875	70	740	70	640	70	640	70	500	Mbps
חטוטח	×4	40	875	40	740	40	640	40	640	40	500	Mbps
	×2	20	875	20	740	20	640	20	640	20	500	Mbps
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	Mbps
SW	_	_	400	_	400	_	400	_	550	_	640	ps
Input jitter tolerance	_	_	500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	_	_	1	_	1	_	1	_	1		1	ms

Notes to Table 1-36:

- Cyclone IV E—LVDS receiver is supported at all I/O Banks.
 Cyclone IV GX—LVDS receiver is supported at I/O Banks 3, 4, 5, 6, 7, 8, and 9.
- (2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

External Memory Interface Specifications

The external memory interfaces for Cyclone IV devices are auto-calibrating and easy to implement.

IOE Programmable Delay

Table 1–40 and Table 1–41 list the IOE programmable delay for Cyclone IV E 1.0 V core voltage devices.

Table 1–40. IOE Programmable Delay on Column Pins for Cyclone IV E 1.0 V Core Voltage Devices (1), (2)

		Number of	Min Offset	Max Offset					
Parameter	Paths Affected			Fast Corner		Slow Corner			Unit
	Setting			C8L	I8L	C8L	C9L	I8L	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	2.054	1.924	3.387	4.017	3.411	ns
Input delay from pin to input register	Pad to I/O input register	8	0	2.010	1.875	3.341	4.252	3.367	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.641	0.631	1.111	1.377	1.124	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.971	0.931	1.684	2.298	1.684	ns

Notes to Table 1-40:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–41. IOE Programmable Delay on Row Pins for Cyclone IV E 1.0 V Core Voltage Devices (1), (2)

		Number of	Min Offset	Max Offset					
Parameter	Paths Affected			Fast Corner		Slow Corner			Unit
	Setting			C8L	I8L	C8L	C9L	I8L	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	2.057	1.921	3.389	4.146	3.412	ns
Input delay from pin to input register	Pad to I/O input register	8	0	2.059	1.919	3.420	4.374	3.441	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.670	0.623	1.160	1.420	1.168	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.960	0.919	1.656	2.258	1.656	ns

Notes to Table 1-41:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting $\bf 0$ as available in the Quartus II software.

I/O Timing

Use the following methods to determine I/O timing:

- the Excel-based I/O Timing
- the Quartus II timing analyzer

The Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get a timing budget estimation as part of the link timing analysis. The Quartus II timing analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after place-and-route is complete.

The Excel-based I/O Timing spreadsheet is downloadable from Cyclone IV Devices Literature website.

Glossary

Table 1–46 lists the glossary for this chapter.

Table 1-46. Glossary (Part 1 of 5)

Letter	Term	Definitions					
Α	_	_					
В	_	_					
С	_	_					
D	_	_					
E	_	_					
F	f _{HSCLK}	High-speed I/O block: High-speed receiver/transmitter input and output clock frequency.					
G	GCLK	Input pin directly to Global Clock network.					
u	GCLK PLL	Input pin to Global Clock network through the PLL.					
Н	HSIODR	High-speed I/O block: Maximum/minimum LVDS data transfer rate (HSIODR = 1/TUI).					
ı	Input Waveforms for the SSTL Differential I/O Standard	V _{IH} V _{REF} V _{IL}					

Table 1-46. Glossary (Part 4 of 5)

ter	Term	Definitions							
	t _C	High-speed receiver and transmitter input and output clock period.							
	Channel-to- channel-skew (TCCS)	High-speed I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.							
	t _{cin}	Delay from the clock pad to the I/O input register.							
	t _{co}	Delay from the clock pad to the I/O output.							
	t _{cout}	Delay from the clock pad to the I/O output register.							
	t _{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.							
	t _{FALL}	Signal high-to-low transition time (80–20%).							
	t _H	Input register hold time.							
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(Receiver\ Input\ Clock\ Frequency\ Multiplication\ Factor) = t_C/w)$.							
	t _{INJITTER}	Period jitter on the PLL clock input.							
	t _{OUTJITTER_DEDCLK}	Period jitter on the dedicated clock output driven by a PLL.							
	t _{OUTJITTER_IO}	Period jitter on the general purpose I/O driven by a PLL.							
	t _{pllcin}	Delay from the PLL inclk pad to the I/O input register.							
-	t _{pllcout}	Delay from the PLL inclk pad to the I/O output register.							
	Transmitter Output Waveform	Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards: Single-Ended Waveform Positive Channel (p) = V _{OH} Negative Channel (n) = V _{OL} Ground Differential Waveform (Mathematical Function of Positive & Negative Channel) V _{OD} 0 V p - n							
	t _{RISE}	Signal low-to-high transition time (20–80%).							
	t _{SU}	Input register setup time.							
J	_	_							

Table 1-46. Glossary (Part 5 of 5)

Letter	Term	Definitions
	V _{CM(DC)}	DC common mode input voltage.
	V _{DIF(AC)}	AC differential input voltage: The minimum AC input differential voltage required for switching.
	V _{DIF(DC)}	DC differential input voltage: The minimum DC input differential voltage required for switching.
	V _{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.
	V _{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	V _{IH}	Voltage input high: The minimum positive voltage applied to the input that is accepted by the device as a logic high.
	V _{IH(AC)}	High-level AC input voltage.
	V _{IH(DC)}	High-level DC input voltage.
	V _{IL}	Voltage input low: The maximum positive voltage applied to the input that is accepted by the device as a logic low.
	V _{IL (AC)}	Low-level AC input voltage.
	V _{IL (DC)}	Low-level DC input voltage.
	V _{IN}	DC input voltage.
	V _{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
v	V _{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter. $V_{OD} = V_{OH} - V_{OL}$.
	V _{OH}	Voltage output high: The maximum positive voltage from an output that the device considers is accepted as the minimum positive high level.
	V _{OL}	Voltage output low: The maximum positive voltage from an output that the device considers is accepted as the maximum positive low level.
	V _{OS}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.
	V _{OX (AC)}	AC differential output cross point voltage: the voltage at which the differential output signals must cross.
	V _{REF}	Reference voltage for the SSTL and HSTL I/O standards.
	V _{REF (AC)}	AC input reference voltage for the SSTL and HSTL I/O standards. $V_{REF(AC)} = V_{REF(DC)} + noise$. The peak-to-peak AC noise on V_{REF} must not exceed 2% of $V_{REF(DC)}$.
	V _{REF (DC)}	DC input reference voltage for the SSTL and HSTL I/O standards.
	V _{SWING (AC)}	AC differential input voltage: AC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	V _{SWING (DC)}	DC differential input voltage: DC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	V _{TT}	Termination voltage for the SSTL and HSTL I/O standards.
	V _{X (AC)}	AC differential input cross point voltage: The voltage at which the differential input signals must cross.
W	_	
X	_	_
Υ	_	_
Z		_

Document Revision History

Table 1–47 lists the revision history for this chapter.

Table 1–47. Document Revision History

Date	Version	Changes				
March 2016	2.0	Updated note (5) in Table 1–21 to remove support for the N148 package.				
October 2014	1.0	Updated maximum value for V _{CCD_PLL} in Table 1–1.				
October 2014	1.9	Removed extended temperature note in Table 1–3.				
December 2013	1.8	Updated Table 1–21 by adding Note (15).				
May 2013	1.7	Updated Table 1–15 by adding Note (4).				
		■ Updated the maximum value for V _I , V _{CCD_PLL} , V _{CCIO} , V _{CC_CLKIN} , V _{CCH_GXB} , and V _{CCA_GXB} Table 1–1.				
		■ Updated Table 1–11 and Table 1–22.				
October 2012	1.6	 Updated Table 1–21 to include peak-to-peak differential input voltage for the Cyclone IV GX transceiver input reference clock. 				
		■ Updated Table 1–29 to include the typical DCLK value.				
		■ Updated the minimum f _{HSCLK} value in Table 1–31, Table 1–32, Table 1–33, Table 1–34, and Table 1–35.				
		 Updated "Maximum Allowed Overshoot or Undershoot Voltage", "Operating Conditions", and "PLL Specifications" sections. 				
November 2011	1.5	■ Updated Table 1–2, Table 1–3, Table 1–4, Table 1–5, Table 1–8, Table 1–9, Table 1–15, Table 1–18, Table 1–19, and Table 1–21.				
		■ Updated Figure 1–1.				
		■ Updated for the Quartus II software version 10.1 release.				
December 2010	1.4	■ Updated Table 1–21 and Table 1–25.				
		■ Minor text edits.				
		Updated for the Quartus II software version 10.0 release:				
		■ Updated Table 1–3, Table 1–4, Table 1–21, Table 1–25, Table 1–28, Table 1–30, Table 1–40, Table 1–41, Table 1–42, Table 1–43, Table 1–44, and Table 1–45.				
July 2010	1.3	■ Updated Figure 1–2 and Figure 1–3.				
		 Removed SW Requirement and TCCS for Cyclone IV Devices tables. 				
		■ Minor text edits.				
		Updated to include automotive devices:				
		Updated the "Operating Conditions" and "PLL Specifications" sections.				
March 2010	1.2	■ Updated Table 1–1, Table 1–8, Table 1–9, Table 1–21, Table 1–26, Table 1–27, Table 1–31, Table 1–32, Table 1–33, Table 1–35, Table 1–36, Table 1–37, Table 1–38, Table 1–40, Table 1–42, and Table 1–43.				
		■ Added Table 1–5 to include ESD for Cyclone IV devices GPIOs and HSSI I/Os.				
		 Added Table 1–44 and Table 1–45 to include IOE programmable delay for Cyclone IV E 1.2 V core voltage devices. 				
		Minor text edits.				